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INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)										APPLICANT Yunlong Sun and Ed Swenson					
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EXAMINER INITIAL		DOCUMENT NUMBER							DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE		
RSP	AA	5	6	1	1	9	4	6	03/97	Leong et al.	219	121.68			
650	AB	5	5	6	9	3	9	8	10/29/96	Sun et al. 219		121.68			
GSE	AC	5	4	7	3	6	2	4	12/05/95	Sun	372	69			
650	AD	5	4	2	0	5	1	5	05/30/95	Uhling et al.	324	601			
650	AE	5	2	9	6	6	7	4	03/22/94	Praschek et al.	219	121.69	09/18/92		
65E	AF	5	2	6	5	1	1	4	11/23/93	Sun et al.	372	69			
690	AG	5 2 6 0 9 6 3				6	3	11/09/93	Baird et al.	372	95				
650	AH	5 0 9 6 8 5 0			0	03/17/92	Lippitt, III	437	173						
650	AI	5	0	5	7	6	6	4	10/15/91	Johnson et al.	219	121.69			
650	AJ	4	9	8	7	2	8	6	01/22/91	Allen	219	121.68			
650	AK	4	9	7	0	3	6	9	11/13/90	Yamazaki et al.	219	121.69			
650	AL	4	7	9	2	7	7	9	12/20/88	Pond et al.	338	195		-	
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G5E	AM			0	6	1	8	2	03/17/94	PCT	H018	3/09			
655	AN	2	1	0	3	8	8	4	02/23/83	UK	H01C	17/24			
			()T	HE	R	DC	CU	JMENTS (Inc	cluding Author, Title, Date	e, Pertinent	Pages, etc.)			
Co	AO	D	ow	et et	al	٠, '	'Re	duc	ing Post-Trim	Drift of Thin-Film Resistors	by Optimizin	g YAG Laser O	atput Character	ristics,"	
67		<u>I</u>	IEEE Transactions on Components, Hybrids and Mfg. Technology, Vol. Ch-1, No. 4, Dec 1978, pp 392-397												
636	AP	G	Gillespie, et al. Applied Optics, Vol. IV, pp 1488 (1985)												
	1.0	J	Jellison, Jr., G.E. et al., "Optical Properties of Heavily Doped Silicon Between 1.5 and 4.1 eV," PHYSICAL												
650	AQ	⊢	REVIEW LETTERS, Vol. 46, No. 21., (May 1981), pub. by The American Physical Society, pp. 1414-1417												
GSE	AR	┺	Chih-Youan Lu et al., IEEE, Transactions on Electron Devices, Vol. 36, No. 6, pp 1056-1061 (6/89)												
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Sheet 2 of 2

FORM PTO-1449 (REV. 7-80)

U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO. 26860/33:43 D

APPLICATION NO.

INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)

APPLICANT Yunlong Sun and Ed Swenson

FILING DATE September 2, 1997 GROUP

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GSE	AA	4	7	9	1	6	3	1	12/03/88	Baumert et al.	372	22	
630	AB	4	7	6	1	7	8	6	08/02/88	Baer	372	10	
69E	AC	4	7	0	8	7	4	7	11/24/87	O'Mara, Jr.	437	19	
680	AD	4	7	0	5	6	9	8	11/10/87	Van Dine	427	53.1	
686	AE	4	3	9	9	3	4	5	08/16/83	Lapham et al.	219	121	
69E	AF	4	2	8	8	7	7	6	09/08/81	Holmes	338	308	
696	AG	4	1	8	2	0	2	4	01/08/80	Cometta	29	571	
	AH												
	AI												
	AJ												
	AK												

FOREIGN PATENT DOCUMENTS

	DOCUMENT										TRANSLATION		
	DOCUMENT NUMBER						DATE	COUNTRY		CLASS	SUBCLASS	YES	NO
AL													
AM													
AN													

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

ESE	AO	Michael J. Mueller, "Functional laser trimming of thin film resistors on silicon ICs," SPIE, Vol. 611,								
675		Laser Processing of Semiconductors and Hybrids (1986), pp. 70-83.								
GSE	AP	SPIE, Vol. 611, Laser Processing of Semiconductors and Hybrids (1986), pp 12-13.								
GSE	AQ	R. H. Wagner, "Functional Laser Trimming an Overview," PROCEEDINGS OF SPIE - THE INTERNATIONAL SOCIETY FOR OPTICAL ENGINEERING, Vol. 611, 21-22 January 1986, Los Angeles, pp 8-17.								
GSE	AR	Weber, "Handbook of Laser Science and Technology," Optical Materials: Part II, CRC Press (10/86)								

EXAMINER

Geoffrey S. Evans

DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.